Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/660,278	YAGAWA, YUICHI	
Examiner	Art Unit	
Apu M. Mofiz	2165	

	SEARCHED					
Class	Subclass	Date	Examiner			
707	1,10, 200, 204 1,7,10	07/13/06				
	204					
705	1,7,10					
705	214					
	223,246	J	J			

INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
Inventor	03/13/06	An			
Search		1			
Eart - USPGPUB - EPO, JPO - BM TBB - DERWENT					
NPL - ACM - IEEE					
1 nfhnet - Google					